

Determination of the refractive index, the absorption coefficient and the thickness of amorphous V_2O_5 thin films from reflectance interference spectra

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Abstract: The absorption coefficient, refractive index and thickness of amorphous vanadium pentoxide thin films have been determined from reflectance interference spectra in the wavelength range of 450-710 nm. In the photon energy range of 2.15-2.70 eV the wavelength dependence of the absorption coefficient obeys Urbach's rule.    1983 with the authors.

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